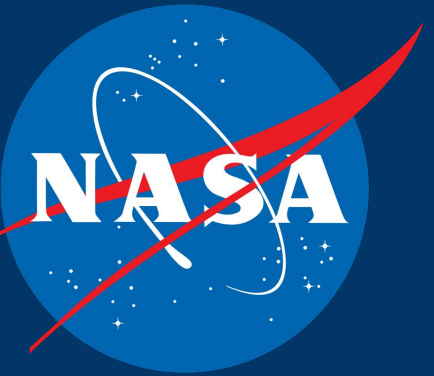
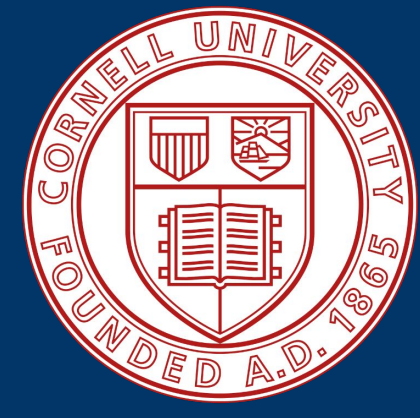


Optimizing the Efficiency of Fabry-Perot Interferometers with Silicon-Substrate Mirrors

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Introduction

Interferometers in ground, airborne, and space observatories have spurred growth in astronomy and astrophysics for decades. We present the novel design of microfabricated, silicon-substrate based mirrors for use in cryogenic Fabry-Perot Interferometers (FPIs) for mid-IR to submm/mm instruments in ground (e.g. CCAT-prime [1,2]), airborne (e.g. HIRMES), and space-based instruments. To achieve high resolving power and optical throughput, we use a combination of inductive and capacitive gold meshes evaporated onto the silicon substrate. The other side of the substrate is plasma etched with a double-layer metamaterial anti-reflection coating (ARC). These silicon-substrate FPIs will enable spectroscopic observations with the upcoming large IR/submm/mm TES bolometer detector arrays. These broad bandwidth of these FPIs will:

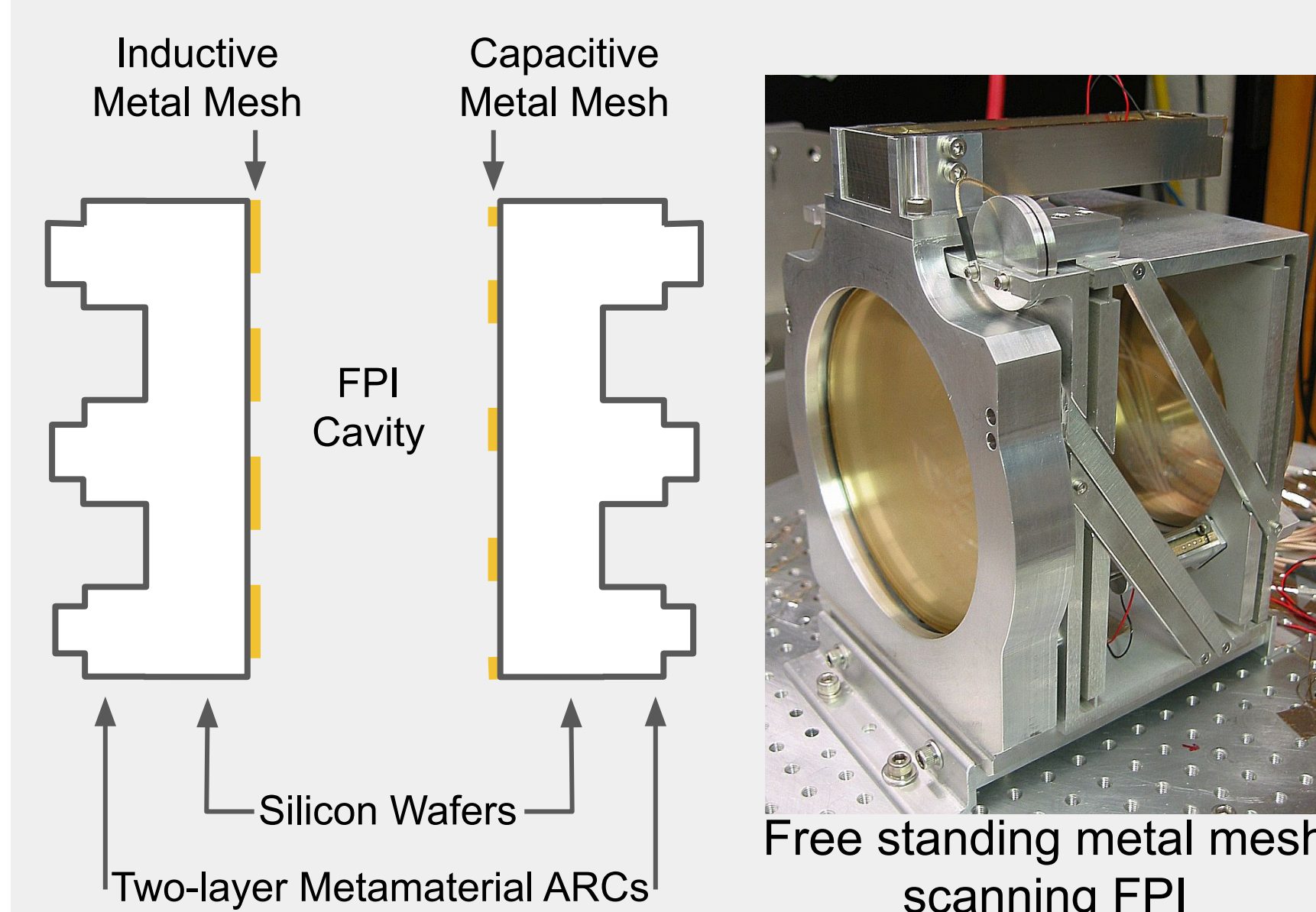
- Efficiently cover the octave bandwidth required for a [CII] intensity mapping spectrometer for Epic of Reionization investigations on CCAT-prime [1]
- Observe a broad set of diagnostic far-infrared fine-structure lines (e.g. [OIII] 52 um to [NII] 122 um) with a single FPI for airborne or space-borne spectroscopy (e.g. HIRMES) [4]

Silicon Substrate FPIs

Far-IR FPIs commonly use free-standing metal meshes as reflectors [6]. Silicon substrate based mirrors promise significant improvements in transmission, bandwidth, and mechanical stability.

Silicon substrate FPIs are comprised of:

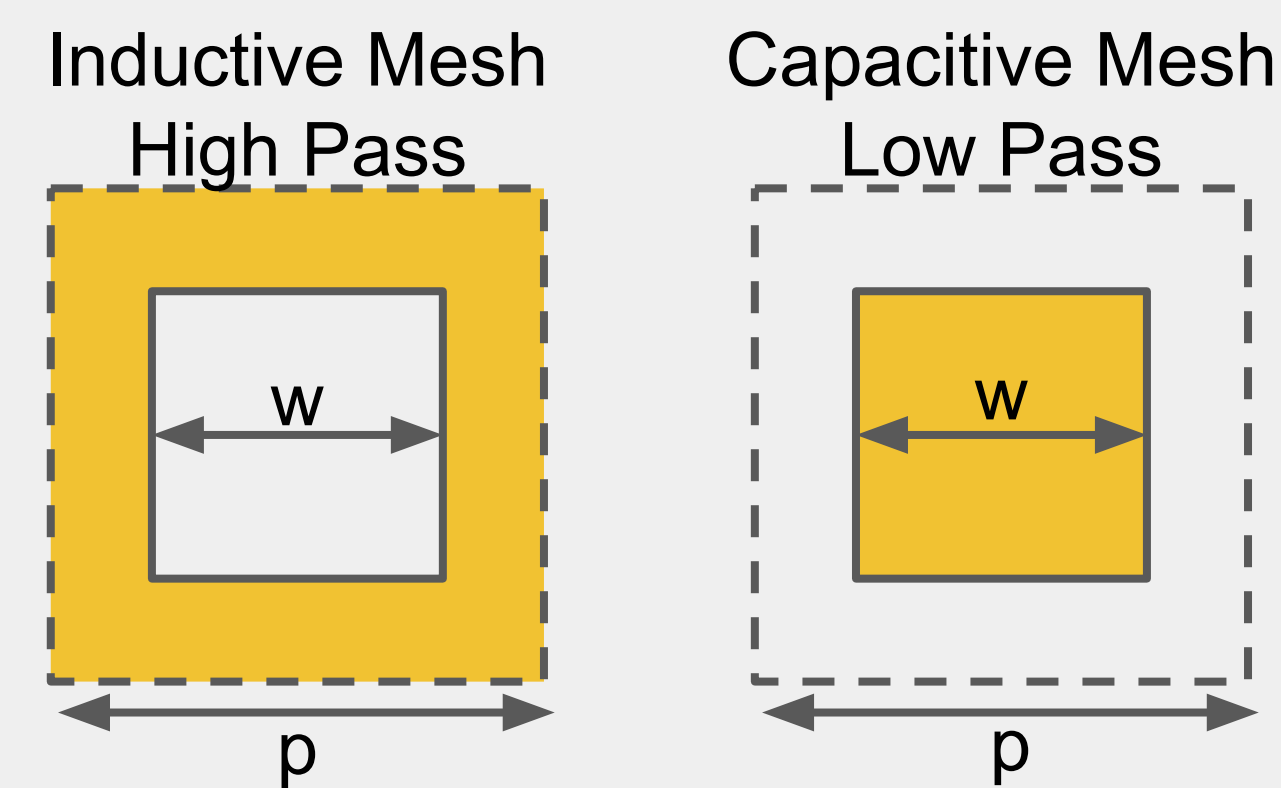
- Metal mesh reflectors on silicon wafers [7]
 - Provide frequency dependent reflectance
 - Provide control of FPI resolving power
- Metamaterial anti-reflection coatings [10]
 - Sub-wavelength structure etched on silicon
 - Mitigate strong Fresnel reflections of silicon
 - Multiple layers → wider bandwidth



Design and Modeling

Metal Meshes

- Inductive and capacitive meshes [5]
 - Form high and low pass filters
 - Diffraction occurs for $\lambda < p$
 - Filter response depends on w/p
- Combining inductive and capacitive
 - Band-pass or band-stop filters
- Filters simulated in CST Microwave Studios

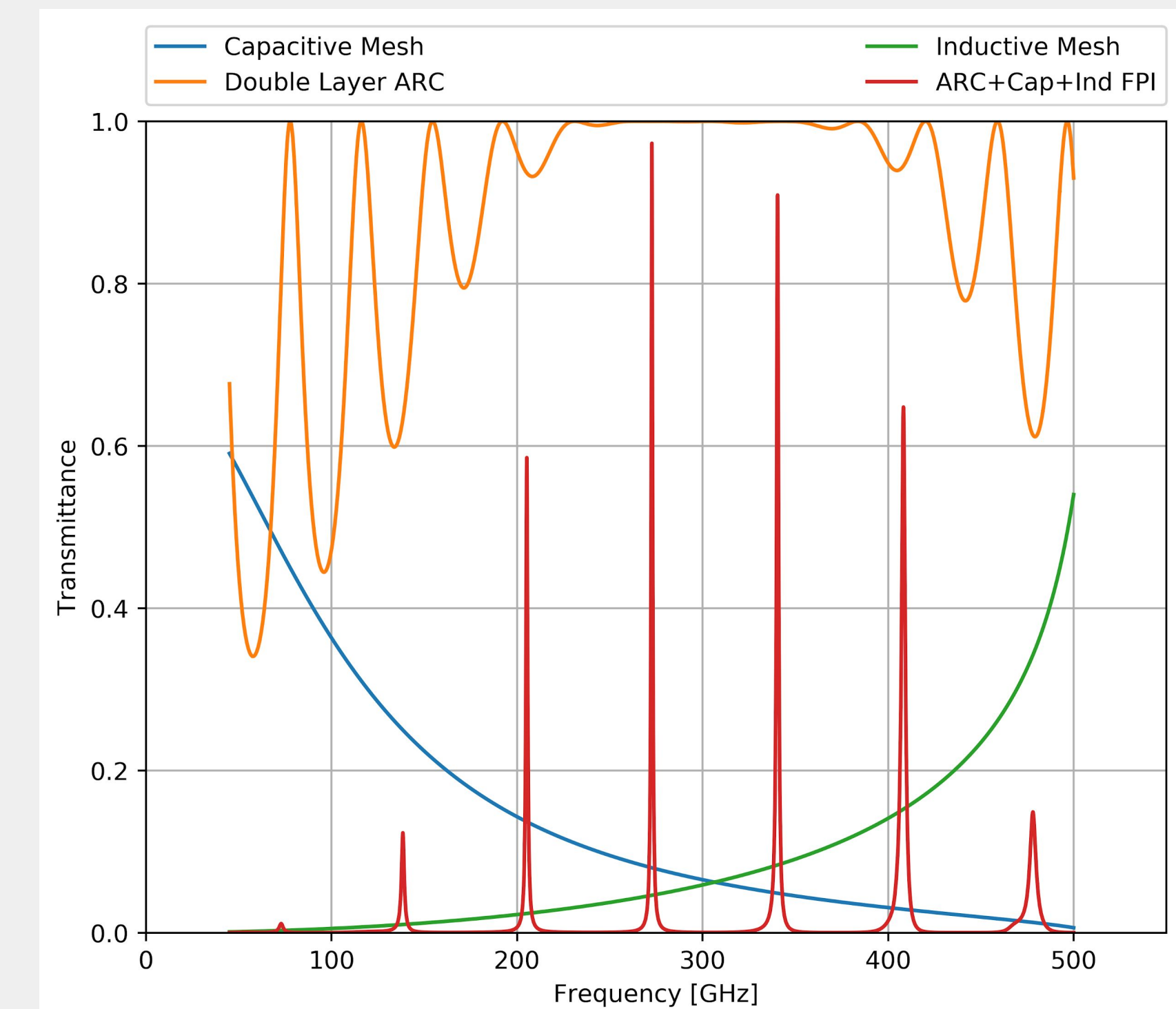


Metamaterial Anti-Reflection Coatings

- Broadband, sub-percent reflections required by FPI
 - To mitigate parasitic resonances
 - To optimize throughput
- Metamaterial benefits:
 - Precision control of ARC efficiency
 - Eliminates thermal contraction issues
- ARC depths, indices, and metamaterial geometry determined using:
 - Theory of layered dielectrics [8]
 - Equivalent circuit model theory [9]
 - Optimized with CST Microwave Studios

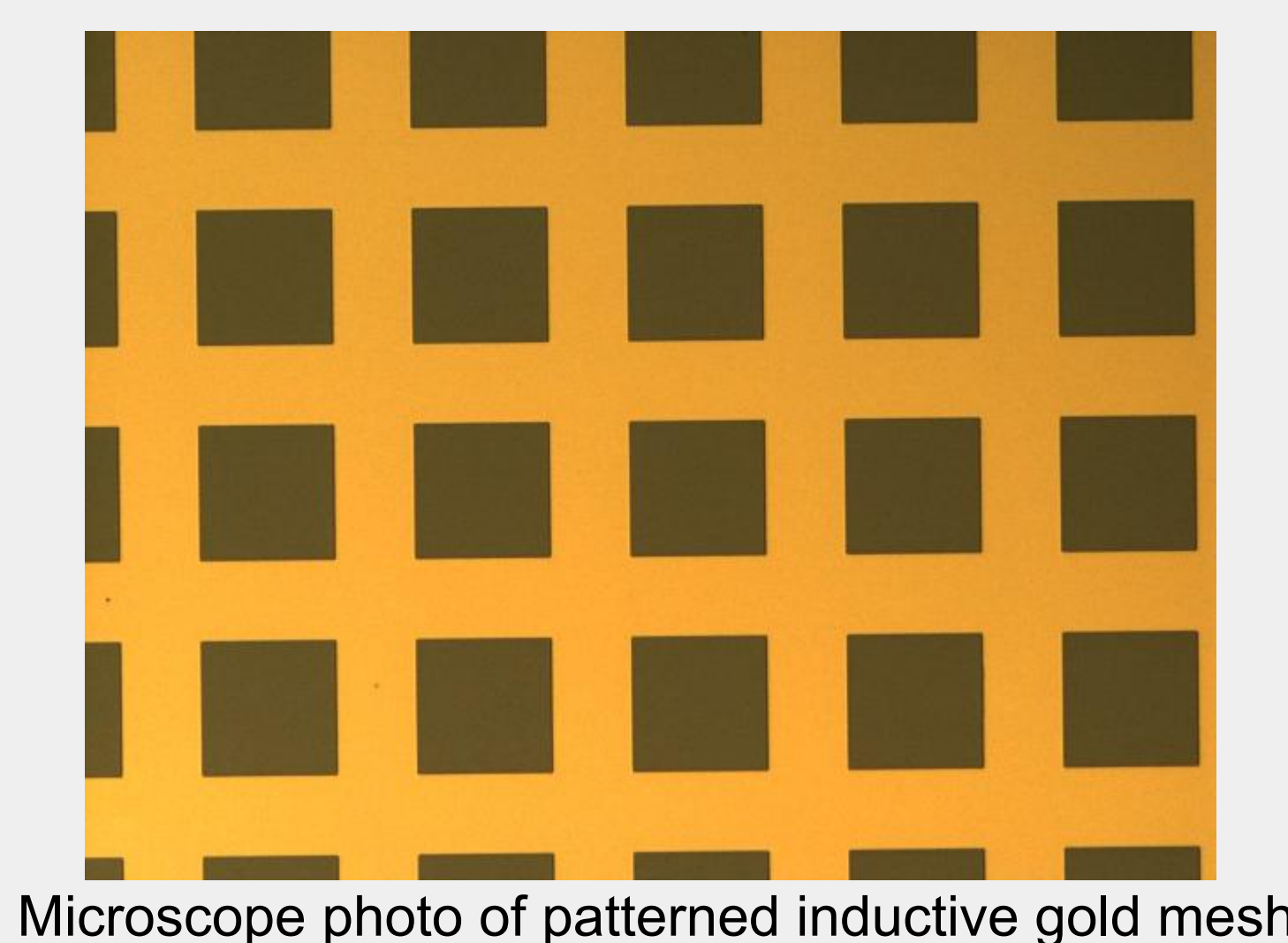
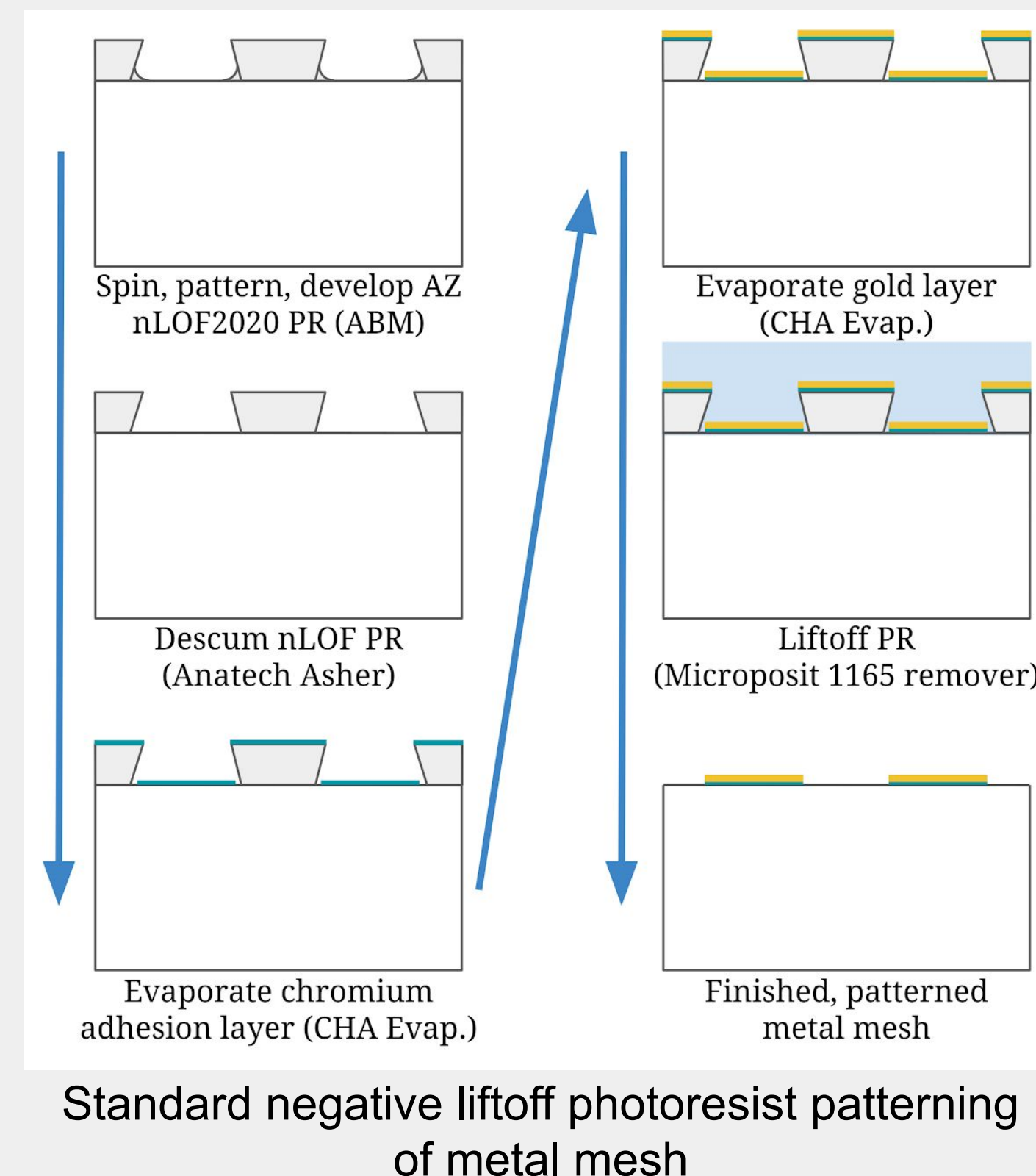
$$\epsilon_r^{\text{eff}} = \left(\frac{a-b}{a} - \frac{b\epsilon_r^{\text{Si}}}{b+(a-b)\epsilon_r^{\text{Si}}} \right)$$

Equivalent Capacitive Circuit Model



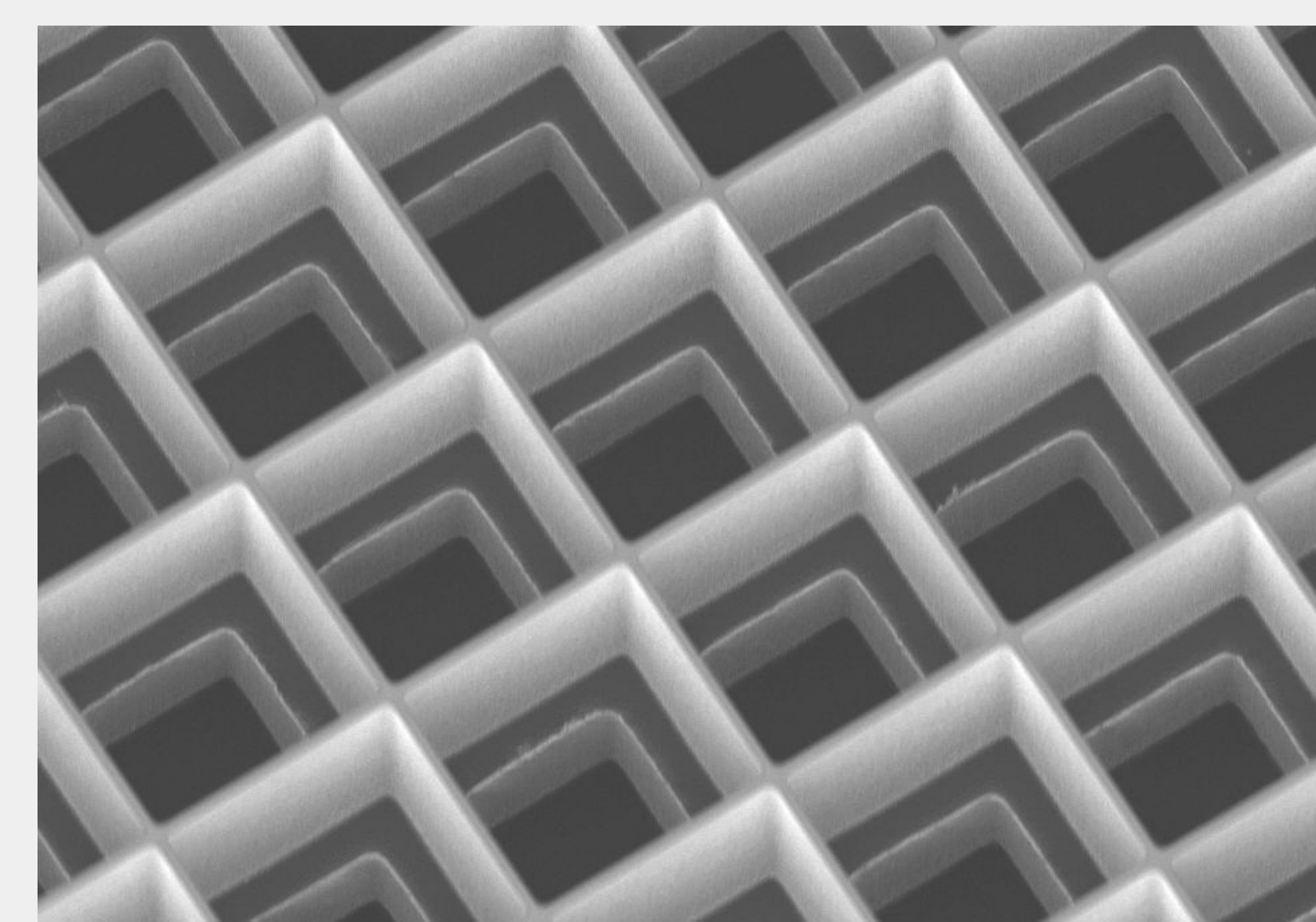
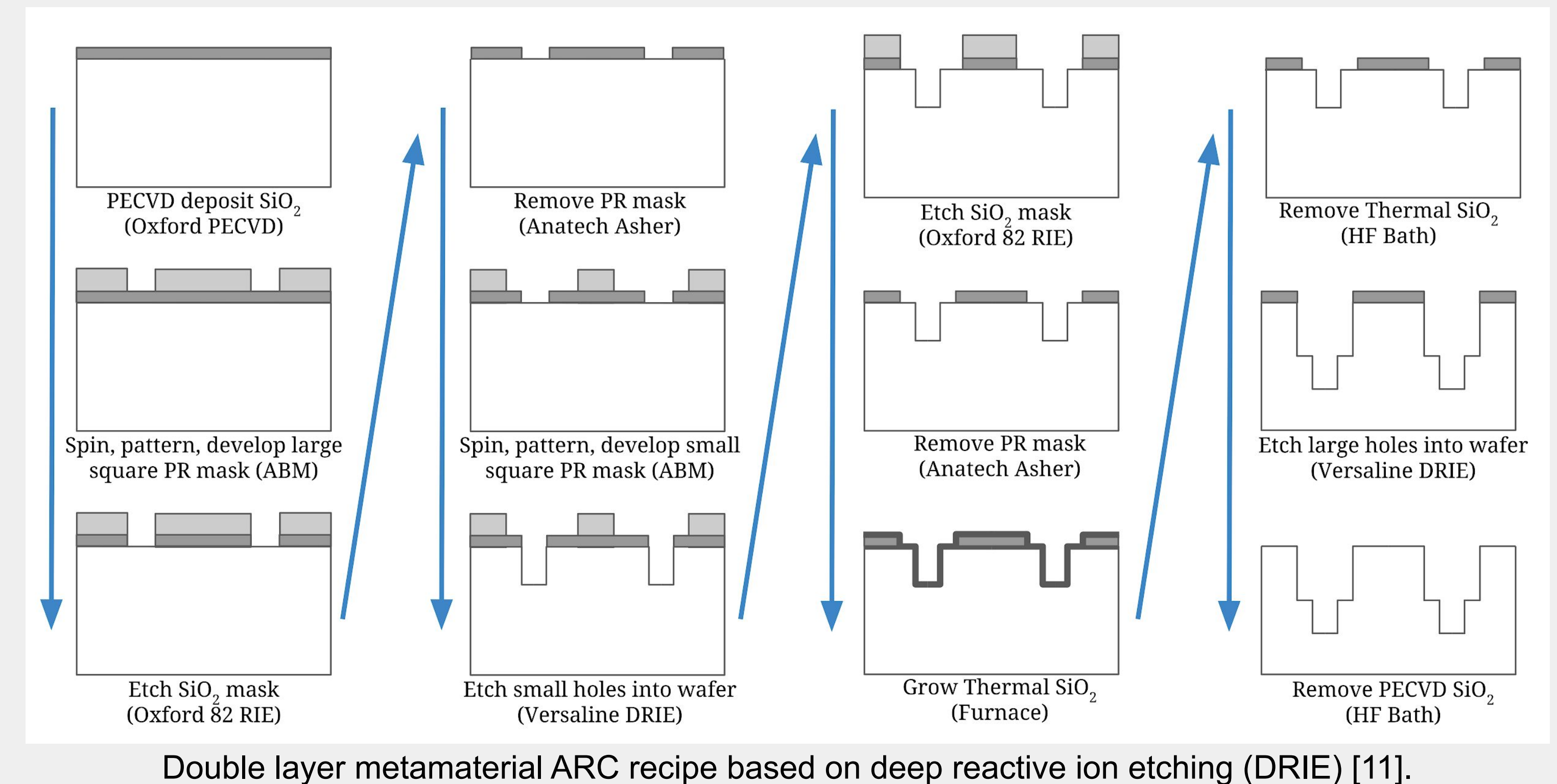
Simulated transmittance of a FPI and comprising two-layer ARC and inductive/capacitive metal meshes calculated with CST Microwave Studios

Metal Mesh Deposition

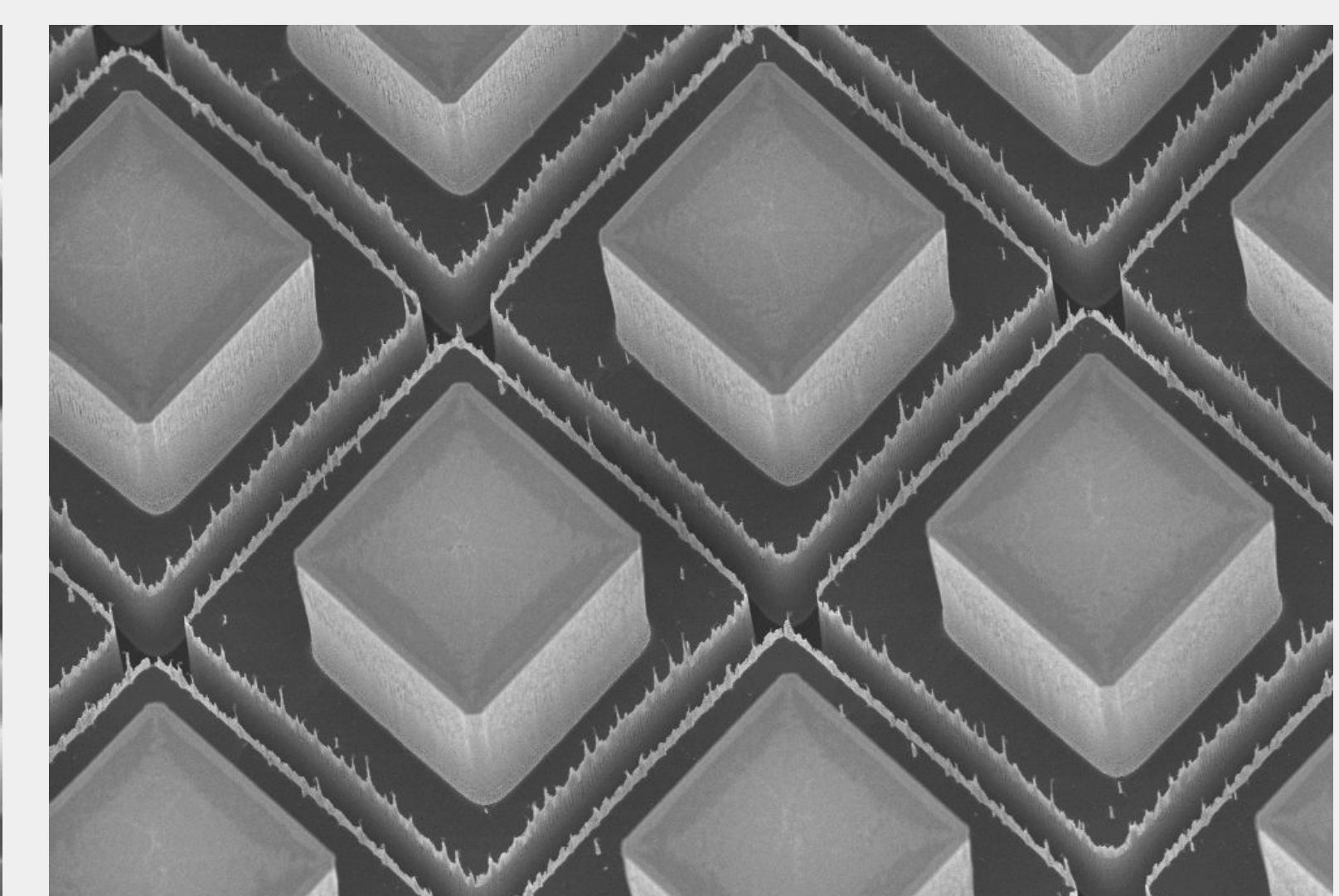


Microscope photo of patterned inductive gold mesh

Metamaterial Anti-Reflection Coating Fabrication



SEM image of double-layer holes ARC optimized for 100um



SEM image of double-layer pillars ARC optimized for 350um

Future Work

- Currently fabricating on optical silicon
 - 1mm broadband double-layer ARCs
 - 1mm metal mesh reflectors
- FTS measurements coming soon.
- “Fixed” FPI of metal meshes on either side of optical silicon wafer, this summer.
- Scanning FPI with pair of mirrors, this fall.
- Exploring superconducting meshes to reduce ohmic losses in mesh filters.

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